

INSTITUTE OF SCIENCE, TECHNOLOGY & ADVANCED STUDIES (VISTAS) (Deemed to be University Estd. u/s 3 of the UGC Act, 1956) PALLAVARAM - CHENNAI ACCREDITED BY NAAC WITH 'A' GRADE Marching Beyond 25 Years Successfully

Facilities Available @ Central Instrumentation Laboratory (CIL), VISTAS

CONFOCAL RAMAN MICROSCOPE- IMAGINING/SPECTROMETER Model Alpha 300R Make Witech, Germany	FIELD EMISSION SCANNING ELECTRON MICROSCOPE (FESEM) WITH ENERGY DISPERSIVE X-RAY SPECTROMETER (EDS) Model Quattro S Make ThermoFisher Scientific, USA	
ATOMIC FORCE MICROSCOPE (AFM) Model Park XE7 Make Park System, Korea	BET SURFACE AREA ANALYSIS Model BETSORP Max Make Microtrac BEL, Japan	
DYNAMIC LIGHT SCATTERING (DLS) Analysis Model Nanotrac Wave II Make Microtrac Inc, USA	SIMULTANEOUS THERMOGRAVIMETER/ DIFFERENTIAL SCANNING CALORIMETER (TGA-DSC) Model TGA-DSC 3+ Make Mettler toledo, Swizerland	
DIFFERENTIAL SCANNING CALORIMETER (DSC) Model DSC 3+ Make Mettler toledo, Switzerland	UV-VIS SPECTROPHOTOMETER Model JAZ Make Oceian optics, USA	
POWDER X-RAY DIFFRACTOMETER (P-XRD) Model SmartLab SE X-Ray Make Rigaku, Japan	ATTENUATED TOTAL REFLECTANCE FOURIER TRANSFORM INFRA-RED SPECTROMETER (ATR-FTIR) Model Spectrum 2 Make PerkinElmer, USA	
REAL TIME-POLYMERASE CHAIN REACTION (RT-PCR)	ELECTROCHEMICAL WORKSTATION	- + +



Model StepOne Make Applied Biosystems, ThermoFishier Scientific

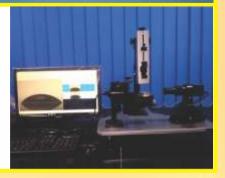
Model 760A Make CH instruments, USA





CONTACT ANGLE METER

Model HO-IAD-CAM-01 Make Holmarch, India



Analysis undertaken, For further details contact: Shri. K. Krishna Kumar Central Instrumentation Laboratory (CIL), VISTAS, Chennai - 600 117. e-mail : technicalofficer.cilab@velsuniv.ac.in / Mobile : 9962506284

Charge details for using the equipment at Central Instrumentation Laboratory (CIL), VISTAS

CONFOCAL RAMAN MICROSCOPE- IMAGINING Raman spectra only Chemical(2D) imaging and analysis spectra Depth profiling and spectra analysis 3D imaging and spectra analysis	S/SPECTROME Academic 1000 2000 3000 7500	TER Industries 1500 3000 5000 10000	FIELD EMISSION SCANNING ELECTRON MICROSCOP DISPERSIVE X-RAY SPECTROMETER FESEM image (5 to 7 images) EDS (One EDS spectra & one elemental mapping) FESEM with EDS (5 images with One EDS spectra & one elemental mapping)		
ATOMIC FORCE MICROSCOPE (AFM)Academic IndustriesNon-Contact mode (4 images per sample)15002000Tapping mode (4 images per sample)20003000Contact mode (4 images per sample)20003000Lateral Force Microscope (LFM) mode20003000Electrochemical In-suite studies750010000		BET SURFACE AREA ANALYSIS Surface Area Adsorption/Desorption isotherm	Academic 2000 2500	4000 5000	
Liquid probe mode Magnetic Force Microscope (MFM) mode Force Modulated Microscope (FMM) mode	2000 2000 2000	3000 3000 3000	SIMULTANEOUS THERMOGRAVIMETER/ DIFFERE CALORIMETER (TGA-DSC) Heating only Heating and Cooling	Academic 1500 2000	Industries 2000 3000
DYNAMIC LIGHT SCATTERING (DLS) Analysis			UV-VIS SPECTROPHOTOMETER		
Particle Size Particle Size with Zeta potential		Industries 2000 3000		Academic 500 300	Industries 1000 500
DIFFERENTIAL SCANNING CALORIMETER (DSC)			ATTENUATED TOTAL REFLECTANCE FOURIER TRANSFORM INFRA-RED SPECTROMETER (ATR-FTIR)		
Heating only Heating and Cooling	Academic 1500 2000	Industries 2000 3000	· · · · · · · · · · · · · · · · · · ·	Academic 300 400 500 750	Industries 700 800 1000 1500
		ELECTROCHEMICAL WORKSTATION			
POWDER X-RAY DIFFRACTOMETER (P-XRD) - 2θ range-5 to 130				Academic	Industries
	Academic 500	Industries 1000	Cyclic Voltammetry (CV) studies (5 cycles at scan rate 20mV/s) Electrochemical Impedance Spectroscopy (EIS)	300 500	500 1000

REAL TIME-POLYMERASE CHAIN REACTION (RT-PCR)

Charges on Request

HIGH PERFORMANCE THIN LAYER CHROMOTOGRAPHY (HPTLC)

Academic	Industries		
1500	3000		
2000	5000		

CONTACT ANGLE METER Academic Industries 300 500

Terms and Condition

Original and Photocopy of DD drawn in favor of "VISTAS, CHENNAI" payable at Chennai, should be submitted at the time of analysis along with sample and request form

Screening

Quantification

- Photocopy of the receipt for payment made by cash should be submitted at the time of analysis along with sample and request form
- Courier the sample, DD and form should be addressed to "Technical Officer, Central Instrumentation Laboratory, Velan Nagar, P.V. Vaithiyalingam Road, Pallavaram, Chennai 600 117, Tamil Nadu, India. Phone- 9962506284"
- For queries contact only through mail technicalofficer.cilab@velsuniv.ac.in

Any publication out of work carried out using CIL facilities should be duly acknowledged as "VELS INSTITUTE OF SCIENCE, TECHNOLOGY & ADVANCED STUDIES (VISTAS), Chennai"